SEMICONDUCTOR IM

150V N-Channel PowerTrench[®] MOSFET

General Description

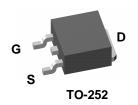
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers.

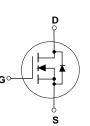
These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable $R_{\text{DS(ON)}}$ specifications.

The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.

Features

- 4.7 A, 150 V. $R_{DS(ON)} = 80 \text{ m}\Omega @ V_{GS} = 10 \text{ V}$ $R_{DS(ON)} = 90 \text{ m}\Omega @ V_{GS} = 6 \text{ V}$
- Low gate charge
- · Fast switching speed
- High performance trench technology for extremely low R_{DS(ON)}
- High power and current handling capability.





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units	
V _{DSS}	Drain-Source Voltage		150	V	
V _{GSS}	Gate-Source Voltage		±20	V	
I _D	Drain Current – Continuous	(Note 1a)	4.7	A	
	Drain Current – Pulsed		30		
PD	Maximum Power Dissipation @ $T_c = 25^{\circ}C$	(Note 1)	70	W	
	@ T _A = 25°C	(Note 1a)	3.2		
	@ T _A = 25°C	(Note 1b)	1.3		
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C	

$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	1.8	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1b)	96	°C/W

Package Marking and Ordering Information

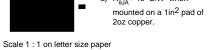
Device Marking	Device	Reel Size	Tape width	Quantity	
FDD2570	FDD2570 FDD2570 13"		16mm	2500 units	

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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-So	burce Avalanche Ratings (Not	e 1)				
W _{DSS}	Single Pulse Drain-Source	$V_{DD} = 75 \text{ V}, \qquad I_D = 4.7 \text{ A}$			375	mJ
I _{AR}	Avalanche Energy Maximum Drain-Source Avalanche Current				4.7	A
Off Char	acteristics	L				
BV _{DSS}	Drain–Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	150			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, Referenced to 25°C		150		mV/°C
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 120 V$, $V_{GS} = 0 V$			1	μA
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate–Body Leakage, Reverse	$V_{GS} = -20 \text{ V} \qquad V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	2	2.6	4	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 µA, Referenced to 25°C		-7		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$ \begin{array}{ll} V_{GS} = 10 \; V, & I_D = 4.7 \; A \\ V_{GS} = 6 \; V, & I_D = 4.5 \; A \\ V_{GS} = 10 \; V, \; I_D = 4.7 \; A, \; T_{J^{\pm}} 125^{\circ} C \end{array} $		60 63 120	80 90 158	mΩ
I _{D(on)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 10 \text{ V}$	30			Α
g fs	Forward Transconductance	$V_{DS}=10~V, \qquad I_{D}=6.3~A$		20		S
Dynamic	Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = 75 V$, $V_{GS} = 0 V$,		1907		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		117		pF
C _{rss}	Reverse Transfer Capacitance			33		pF
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn–On Delay Time	$V_{DD} = 75 \text{ V}, \qquad I_D = 1 \text{ A},$		12	19	ns
t _r	Turn–On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		7	14	ns
t _{d(off)}	Turn–Off Delay Time			41	65	ns
t _f	Turn-Off Fall Time			21	34	ns
Qg	Total Gate Charge	$V_{DS} = 75 V$, $I_D = 4.7 A$,		39	62	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		7		nC
Q _{gd}	Gate–Drain Charge			9		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
ls	Maximum Continuous Drain-Sourc	e Diode Forward Current			2.7	А
V _{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \ V, I_S = 2.7 \ A \qquad (\text{Note 2})$		0.7	1.2	V

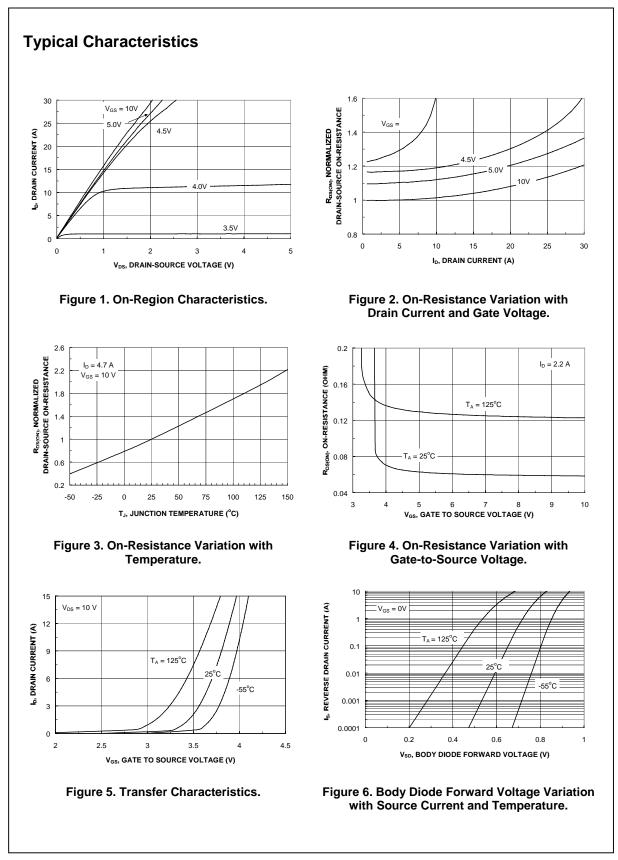
b) R_{θJA}= 96^oC/W on a minimum mounting pad.

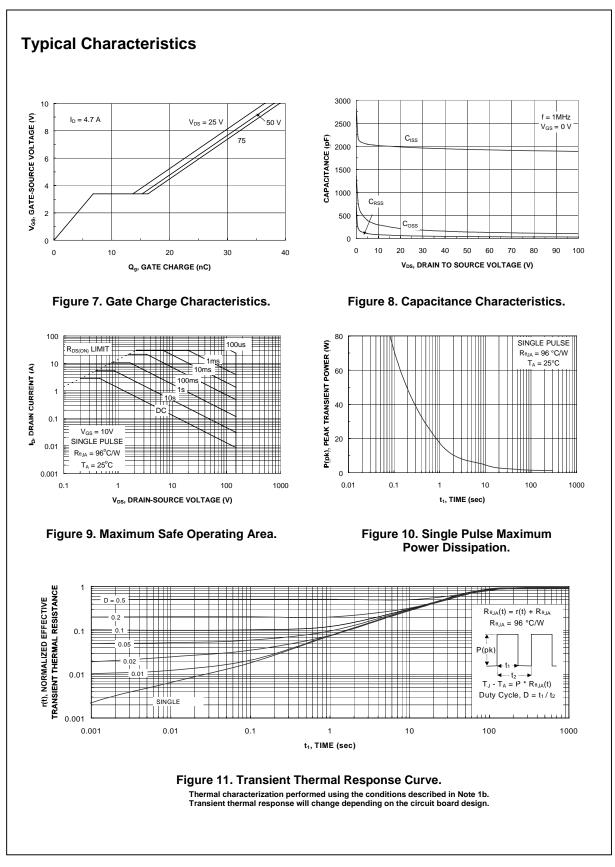




2. Pulse Test: Pulse Width < 300 μ s, Duty Cycle < 2.0%

a) $\rm R_{_{\theta JA}}{=}~40^{o}C/W$ when





FDD2570 Rev C(W)

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